New features in data collection and beamline controls
As of October 5, 2012

General
- A control panel is implemented under Tools → Options
- The CCD binning mode can be changed for screening (in control panel), rastering (in raster tab) and data collection (in control panel) between 72 μm and 144 μm size pixels
- File and directory selection dialogs are improved

Hutch tab
- Beam alignment graphs are integrated in the hutch tab

Sample tab:
- Measured full beamsize is shown on Highres tab beam display options as Full Width at Half-Max. It is also saved in the experimental log file.
- When main Sample tab or peel-out Sample tab window is resized, the video and diffraction image will resize accordingly.

Screening tab
- Diffraction-based centering is an option during screening
- Beam size selection added to screening tab data collection parameters.
- Time remaining till next warm-up is displayed below the warm-up button on screening tab.
- New button added for popup window to show the sample status

Raster tab:
- Diffraction rastering can be done with still images

Collect tab:
- fast_dp was added as a default for data processing.
- Data processing works for multiple sites from vector/raster data collection, vector collection with overlaps and inverse beam. Combined mtz file available in the processing directory.
- Strategy and Data processing results are automatically saved to excel file.

Scan tab:
- Chooch results for edge scans are shown immediately after the scan finishes.